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	Application No.	Applicant(s)
	10/604,244	TAI ET AL.
Notice of Allowability	Examiner	Art Unit
	Toan M. Le	2863
The MAILING DATE of this communication apperature All claims being allowable, PROSECUTION ON THE MERITS IS herewith (or previously mailed), a Notice of Allowance (PTOL-85) NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RI of the Office or upon petition by the applicant. See 37 CFR 1.313	(OR REMAINS) CLOSED in this ap or other appropriate communication GHTS. This application is subject to	plication. If not included n will be mailed in due course. THIS
1. This communication is responsive to 3/28/05.		
2. The allowed claim(s) is/are 1-3 and 6-20.		
3. \boxtimes The drawings filed on <u>03 July 2003</u> are accepted by the Ex	aminer.	
4.		
Attachment(s) 1. ☑ Notice of References Cited (PTO-892) 2. ☐ Notice of Draftperson's Patent Drawing Review (PTO-948) 3. ☐ Information Disclosure Statements (PTO-1449 or PTO/SB/0 Paper No./Mail Date 4. ☐ Examiner's Comment Regarding Requirement for Deposit of Biological Material	6. ☐ Interview Summary Paper No./Mail Da 8), 7. ☐ Examiner's Amenda	tè "

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DETAILED ACTION

Continued Examination Under 37 CFR 1.114

A request for continued examination under 37 CFR 1.114, including the fee set forth in 37 CFR 1.17(e), was filed in this application after final rejection. Since this application is eligible for continued examination under 37 CFR 1.114, and the fee set forth in 37 CFR 1.17(e) has been timely paid, the finality of the previous Office action has been withdrawn pursuant to 37 CFR 1.114. Applicant's submission filed on 3/28/05 has been entered.

Allowable Subject Matter

Claims 1-3 and 6-20 are allowed.

Claims 1-3 and 6-16 are allowable over the prior art of record, none of the prior art whether together singularly or in combination to teach the claimed combination as recited. The closest reference No. 6,618,682 does not disclose or suggest the improvement of the instant application comprises the steps of using the in-line quality control (QC) test parameter of the wafer and the searched test parameters in the sample test item of the high-yield product stocks stored in a database to generate a correlation to illustrate the relationship between the in-line QC test item and the sample test item and using the in-line QC test parameter of the wafer and the correlation to predict a test parameter for the wafer in the sample test item/wafer test item in analyzing in-line quality control test parameters, instead '682 teaches a system and method for adaptive optimizing of a test procedure to determine the best set of tests to run to optimize test time using in-line test parameters, wafer test item, and expert system database.

Claims 17-20 are allowable over the prior art of record, none of the prior art whether together singularly or in combination to teach the claimed combination as recited. The closest

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reference No. 6,618,682 does not disclose or suggest the improvement of the instant application comprises the steps of classifying the lots of products being tested into two groups comprising a qualified group and a failed group corresponding to a first spec, searching a database for a process step and equipments used in the process step for the two groups in order to determine the faulty equipment being used using the in-line QC test parameters of the failed group of products and the searched test parameters in the sample/wafer test item of the high-yield products to generate a correlation to illustrate the relationship between the in-line QC test item and the sample/wafer test item in analyzing in-line QC test parameters.

Reference '682 teaches a system and method for adaptive optimizing of a test procedure to determine the best set of tests to run to optimize test time using in-line test parameters, wafer test item, and expert system database

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Toan M Le whose telephone number is (571) 272-2276. The examiner can normally be reached on Monday through Friday from 9:00 A.M. to 5:30 P.M..

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, John Barlow can be reached on (571) 272-2269. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306. Information

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regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pairdirect.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

Toan Le

May 16, 2005

Supervisory Patent Examiner **Technology Center 2800**

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